

SEM A



GENERAL INFORMATION

Manufacturer : JEOL

Model : JSM 840

- **Electron gun :**
 - Tungsten filament
- **Acceleration voltage :**
 - 200V – 40kV
- **Stage :**
 - Large specimen, full eucentric goniometer stage
 - X 0 – 50 mm
 - Y 0 – 70 mm
 - Z 8 – 48 mm
 - T 0 – 90 degrees
 - R 0 – 360 degrees
- **Specimen holders/ max. specimen size:**
 - Thickness 8 mm, Hight=10mm, Lenght ≈ 20mm, EBSD/tilted samples
 - ϕ 25 mm, H= 20mm, adjustable hight, without tilting
 - ϕ 50 mm, H= 10mm, without tilting
 - ϕ 100 mm, H= 10mm, without tilting
- **Resolution :**
 - 4.0 nm SE
 - 10.0 nm BSE
- **Magnification :**
 - 10X – 300.000X
- **Detectors :**
 - Secondary Electron Detector, SE
 - Solid State Backscattered Detector, BSE
 - NORDIF EBSD Detector
 - NORDIF Absorbed Electron Detector
- **Image recording and analysis system :**
 - Digitized Images